

Performance Specification for Cable-to-Terminal Electrical Crimps

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PERFORMANCE SPECIFICATION FOR CABLE-TO-TERMINAL ELECTRICAL CRIMPS

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1. SCOPE

IMPORTANT NOTICE: In any intended vehicle application, if the products covered by this specification are, or may be, subjected to conditions beyond those described in this document, they must pass special tests simulating the actual conditions to be encountered before they can be considered acceptable for actual vehicle application. Products certified by their supplier as having passed specific applicable portions of this specification are not to be used in applications where conditions may exceed those for which the product has been satisfactorily tested.

The Authorized Person is the final authority as to what tests are to be performed on his or her parts and for what purpose these tests are required. He or she is also the final authority for resolving any questions related to testing to this specification and to authorizing any deviations to the equipment or procedures contained in this specification. Any such deviation must be documented and included in the final test report.

1. This specification defines basic test methods and requirements for solder-less crimped connections.

Note: This specification was developed for use with stranded automotive copper wire. Wire types using compressed, compacted, or solid core construction or other core materials (clad, steel core, etc.) need to be reviewed to determine if this specification is applicable.

2. Grip applications validated to this specification supersede any **crimp information** on the component prints. The terminal supplier has the primary responsibility for testing and selection of crimp tooling and to supply detailed crimp information or make crimp tooling available to the wiring assembly supplier actually doing the production crimping. If the wiring supplier deviates from this information, the information is not available, or the information does not produce an acceptable crimp as defined by this document, the responsibility for testing to this specification lies with the wiring harness supplier. Getting approval from the customer with appropriate test data showing that the grip will function as defined by this specification also lies with the wiring harness supplier.
3. New or revised terminals shall be designed to meet this specification.
4. All grip applications shall meet this specification. Deviations must be approved by the customer engineering department.
5. Electrical tests in this specification have been proven by past experience to ensure that crimped connections will meet the requirements in SAE/USCAR-2 and SAE/USCAR-20 by including Thermal Shock, Temperature Humidity, and Power Current Cycling. Testing and electrical acceptance criteria will detect defects in crimp tooling geometry, plating quality, inadequate strand distribution in the grip, or cable stranding. Grip applications that have passed SAE/USCAR-2 and SAE/USCAR-20 normally have only passed the nominal crimp height and usually only with the largest wire size. Therefore, grips within the production crimp height range may not necessarily pass this test.

6. Procedures included within this specification are intended to cover performance testing and development of electrical terminal grips that are part of the electrical connection systems in low voltage (0 - 48 VDC) road vehicle applications at ambient temperatures of 125°C maximum. The OEM customer must approve use of these test procedures for use at voltages and temperatures beyond these limits.
7. These procedures are applicable to terminals used for in-line, header, edge board, and device connector systems as well as eyelet or battery terminals.

1.1 Crimping Parameters

1.1.1 The Crimped connection performance is characterized by:

Mechanical performance is measured by terminal to conductor Pull-Out Force.

Electrical performance is measured by terminal-to-conductor Resistance and or Voltage Drop.

1.1.2 The geometry of a conductor crimp is characterized by:

Conductor crimp height (CCH)

Conductor crimp width (CCW)

Insulation crimp height (ICH)

Insulation crimp width (ICW)

Cut-off

End of conductor

End of insulation

Bellmouth (flare)

Burr (anvil flash) dimension on the base of the conductor grip

Step between the core and insulation tools

Crimp tooling geometry

2. REFERENCED DOCUMENTS

SAE/USCAR-2 Performance Specification for Automotive Electrical Connector Systems

SAE/USCAR-20 Field Correlated Life Test Supplement to SAE/USCAR-2

2.1 Document Hierarchy

To claim conformance to this specification, the tooling and process settings used to crimp a terminal/wire application must be traceable to a passed USCAR-21 test using the same settings. The tooling and process used to meet USCAR-21 are very likely to be different than what is listed on a terminal drawing or process sheet developed per another specification. Therefore, the settings traceable to USCAR-21 must supersede all documentation to the contrary (including crimp information on the part drawings) in order to claim compliance.

In the event there is a conflict between performance specification, part drawings, and other related standards or specifications, it first must meet the SCOPE 1.0 in paragraph 2 otherwise the requirements shall be prioritized as follows.

- 1st- Applicable FMVSS requirements and other applicable state and Federal requirements.
- 2nd- Applicable part drawings
- 3rd - Applicable product design specification(s).
- 4th- Automotive Industry Action Group (AIAG) Production Part Approval Process (PPAP)
- 5th- Applicable USCAR/EWCAP performance specifications
- 6th- Other applicable standards and specifications

2.2 Test Request/Order

2.2.1 Samples, Test Type and Special Tests

The laboratory test request/order shall provide location and documentation of test samples, identify the type of test to be performed (development, validation, special purpose, etc.) and describe any special tests that are not a part of this specification. Any required revisions to, or deviations from any tests in this specification must include detailed instructions for each change.

2.3 Materials and Processes Specifications

Suppliers are expected to adhere to the appropriate Materials and Process that are referenced in this specification and any associated drawings and reference documents.

Unless otherwise specified or required by law, suppliers are expected to use the most recent versions of any applicable drawings, reference documents, and standards.

2.4 Other Referenced Documents

- SAE J1128: Low Tension Primary Cable
- SAE J1127: Battery Cable
- JISC 3406: Low Tension Primary Cable
- ISO/DIN 6722 Low Tension Primary Cable
- AIAG: Measurement Systems Analysis Reference Manual
- SAE/USCAR-2 Performance Specification for Automotive Electrical Connector Systems
- SAE/USCAR-20 Field Correlated Life Test Supplement to SAE/USCAR-2

3. GENERAL REQUIREMENTS

3.1 Record Retention

The supplier shall maintain a central file for the storage of laboratory reports and calibration records. Such record storage must be in accordance with established ISO and AIAG policies and practices.

3.2 Sample Documentation

All test samples shall be identified in accordance with the requirements of ISO and the AIAG PPAP.

3.3 Sample Size

Minimum sample sizes are given for each test in this specification. A greater number of samples may be required by the test request/order. However, no part or device may be represented as having met this specification unless the minimum sample size has been tested and all samples of the group tested have met the applicable Acceptance Criteria for that test. It is never permissible to test a larger group, then select the minimum sample size from among those that passed and represent that this specification has been met. It is permissible to include additional groups of crimp heights to insure there at least 3 consecutive crimp heights (nominal and +/- 1 crimp height tolerance) will meet the requirements. Any alternative sample size and/or methodologies must be approved by the Authorized Person.

3.4 Default Test Tolerances

Default Tolerances, expressed as a percentage of the nominal value unless otherwise indicated:

- A. Temperature = $\pm 3^{\circ}\text{C}$
- B. Voltage = $\pm 5\%$
- C. Current = $\pm 5\%$
- D. Resistance = $\pm 5\%$
- E. Length = $\pm 5\%$
- F. Time = $\pm 5\%$
- G. Force = $\pm 5\%$
- H. Relative Humidity = $\pm 5\%$

3.5 Test Default Conditions

When specific test conditions are not given either in the product design specification, the test request/order or elsewhere in this specification, the following basic conditions shall apply:

- A. Room Temperature = $23 \pm 5^{\circ}\text{C}$
- B. Relative Humidity = Ambient
- C. Voltage = $14.0 \pm 0.1\text{ VDC}$

3.6 Equipment

Neither the list shown in Table 3-6, nor the list in each test section is all-inclusive. It is meant to highlight specialized equipment or devices with particular accuracy requirements. Many other items of customary laboratory equipment and supplies will also be required.

DESCRIPTION	REQUIREMENTS
DC Power Supply (Regulated)	⇒ 0-20 V ...200A or ⇒ 0~20V current sized as required.
Micro-ohmmeter	⇒ 0-20 mV maximum open circuit voltage ⇒ 0-100 mA maximum test current ⇒ 0.03 mΩ/mV resolution
Digital Multimeter (DMM)	Capable of measuring the following: ⇒ .001 - 50 Volts DC with an accuracy of 0.5% of full scale ⇒ 0-10 MegOhms with an accuracy of 0.5% of full scale
Current Shunts	100 mA or as required with accuracy of $\pm 1\%$ of nominal
Millivolt Meter	Capable of measuring 0-100 mV DC an accuracy of 0.5 mV or better
Thermocouples	Type "J" or "T" as required
Force Tester	Capable of an accuracy of $\leq 1\%$ of measurement
Data Logger	As Required
Temperature Cycling and/or Thermal shock Chamber	⇒ -40°C to 125°C ⇒ 0% to 98% RH
Forced Air Oven	⇒ +85 ± 3 °C
Temperature Chamber	⇒ -40 +/- 3°C
Temperature/Humidity Chamber	⇒ 95 to 98% RH at +65 +/- 3°C

Note: Use of equipment with a lesser range is acceptable for specific tests where the required range for that test can be met. The equipment range specified does not preclude use of equipment with a larger range, but the accuracy must remain within the specified tolerance. For example, a DMM with a range of 0-100 volts could be substituted for one specified as 0-50 volts, with the provision that the accuracy could be maintained as 0.25 mV or better.

Table 3.6 - Equipment

3.7 Test Order and Set-Up

Diagrams are provided where necessary to clarify the details of the various test procedures. The tests in each section must be performed in the order given unless otherwise specified in the test request/order. Construction details for selected test fixtures and equipment are provided in each section.

3.8 Definitions and Glossary of Terms

Terms defined in the definitions or glossary are capitalized (i.e. Room Temperature, Steady State, PLR, etc.). A list of definitions is provided in Appendix B. A glossary of terms is provided in Appendix C.

3.9 Measurement Resolution

Unless otherwise specified, meters and gages used in measurements of the test sample(s) shall be capable of measuring with a resolution one decimal place better than the specified value. For example, even though a wire diameter specified as 0.1 mm might actually be the same as one specified as 0.10 mm, calipers capable of 0.01 mm resolution may be used to measure the first wire but a micrometer with 0.001 mm resolution is required to measure the second wire.

3.10 Test Repeatability & Calibration

All equipment used for test sample evaluation shall be calibrated and maintained according to the applicable standards and requirements set forth by ISO and the AIAG publication Measurement Systems Analysis Reference Manual. Copies of this Manual can be obtained from the AIAG by calling (248) 358-3570 or writing to AIAG, Dept. 77839, Post Office Box 77000, Detroit, MI 48277-0839, Attn: Customer Service. Information may also be obtained at the AIAG web site, www.aiag.org. Documentation is to be recorded and retained in accordance with Section 4.1 of this SAE/USCAR specification.

A list of instruments and equipment used, date of the last calibration, and when the next calibration is due is to be included in each test report.

3.11 Conformance Determination

Test conformance shall be determined by the performance requirements of the test being conducted. All samples must satisfy the performance requirements regardless of sample age, test cycles, or test temperature, except where a test to failure is specified.

Note: Additional sample groups with alternate crimp heights may be tested to help determine the nominal and min/max crimp height for a given terminal/wire combination. Three consecutive crimp height groups (Nominal, +1 tolerance, and -1 tolerance) must meet the requirements but all groups tested need not pass.

4. TEST & ACCEPTANCE REQUIREMENTS

4.1 General Testing Requirements

The test procedures that follow were written as stand-alone tests and may be used as such. However, they are normally used in a sequential test format and common sense is required to overcome any redundancies in sample preparation or in procedures. For example, if samples have already been prepared for the preceding test in a sequence, it should be obvious that the sample preparation step for that individual test (included so that test can be used as a stand alone test) should be skipped. Should any conflicts or questions arise concerning procedures and/or requirements, contact the Authorized Person. Any test plan approved by the Authorized Person that shows compliance to the minimum performance requirements with test data is acceptable.

Note: In this specification, the test requirement for terminals crimped on wire $>5\text{mm}^2$ has changed from 4.5.2 (ENV) using 4.5.3 Dry Circuit resistance measurement to 4.5.2 using the 4.5.6 Voltage drop measurement method.

Note: Previously validated high current terminations that meet the Acceptance Criteria 4.5.6.5 may be considered compliant even if a different test method was used to establish those values. All new applications must be validated to the latest revision level of this specification.

4.1.1 Dimensional Characteristics

Part construction shall conform to the dimensions, shape, and detail attributes specified on the latest revision of the applicable part drawing(s).

4.1.2 Material Characteristics

All material used in each test sample shall conform to the material specifications on the latest revision of the applicable part drawing(s).

1. Any engineering development, prototype, or production part may be submitted for test.
2. The samples submitted for test should be identified by description, part number, and revision letter.
3. For validation testing, all parts are to be in their "as furnished for vehicle assembly" condition when testing begins. For example, electrical terminals typically have residual die lubricant on them when finally assembled into a vehicle. This same condition must prevail for test samples.
4. Samples submitted for any test shall be prepared per Appendix E.

4.2 Visual Inspection

4.2.1 Purpose

This test is used to document the physical appearance of test samples and to assist in the evaluation of the effects of environmental conditioning on test samples. A comparison can then be made with other test samples. Examinations in most cases can be accomplished by a person with normal or corrected vision, and normal color sensitivity, under cool white fluorescent lighting. Photographs and/or videos are encouraged as a more complete means of documentation. An appropriately identified untested sample from each test group must be retained for post-test physical comparisons if photographs/video's are not taken.

4.2.2 Samples

1. The samples should conform to the requirements of the specified conditioning and any additional measurements that are to be performed.
2. For purposes of comparison and especially when only subtle appearance changes are anticipated, it is desirable to submit an additional sample to serve as a control.

4.2.3 Equipment

Video/photography equipment.

4.2.4 Procedure

1. Visually examine each test specimen prior to testing and/or conditioning, noting in detail any manufacturing or material defects such as cracks, bending, deformation, etc. When specified in the test request/order, take photographs and/or video recordings of representative samples to be tested and keep a properly labeled control sample.
2. After testing and/or conditioning, re-examine each test sample and note in detail any observable changes, such as physical distortions, cracks, etc. Compare the tested and/or conditioned samples to the control samples, the videos, and/or the photographs, recording any differences in the test report. The Authorized Person will need to provide an additional sample for this purpose.
3. If the terminal supplier's appearance requirements are more strict than those specified below, then the terminal supplier specifications should be applied.
4. Return test samples to requestor after all tests are completed and all necessary data have been obtained.

4.2.5 Acceptance Criteria

1. General Appearance – Refer to Figure 4.2.5. The crimping operation should not affect the contact, locking, connector mating, or insertion functions of the terminal. These characteristics are verified as part of USCAR -2 testing.

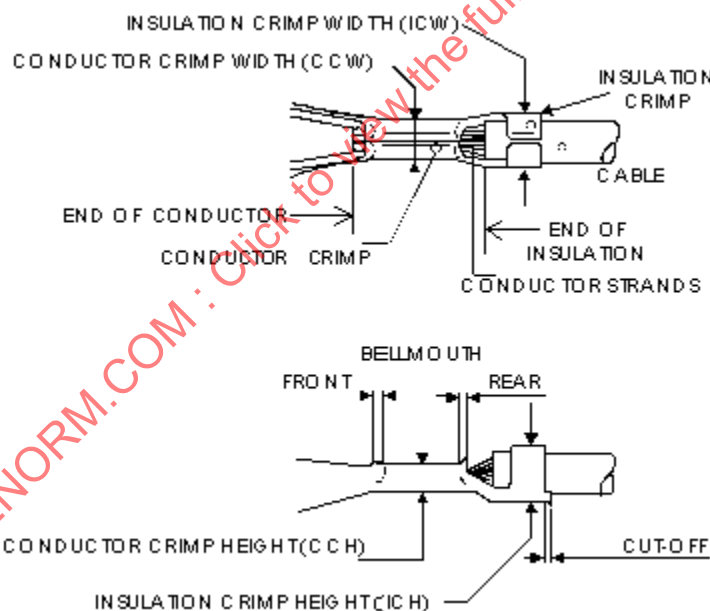


Figure 4.2.5: Appearance Acceptance Criteria

2. End of conductor

The end of conductor must extend beyond the front edge of the conductor grip. The insertion and locking functions of the terminal must not be affected by the projecting end of the conductor. Mat seals (plug through seals) must not be damaged by the core, and may require core depressors and strip length control to depress the core in front of the core wing.

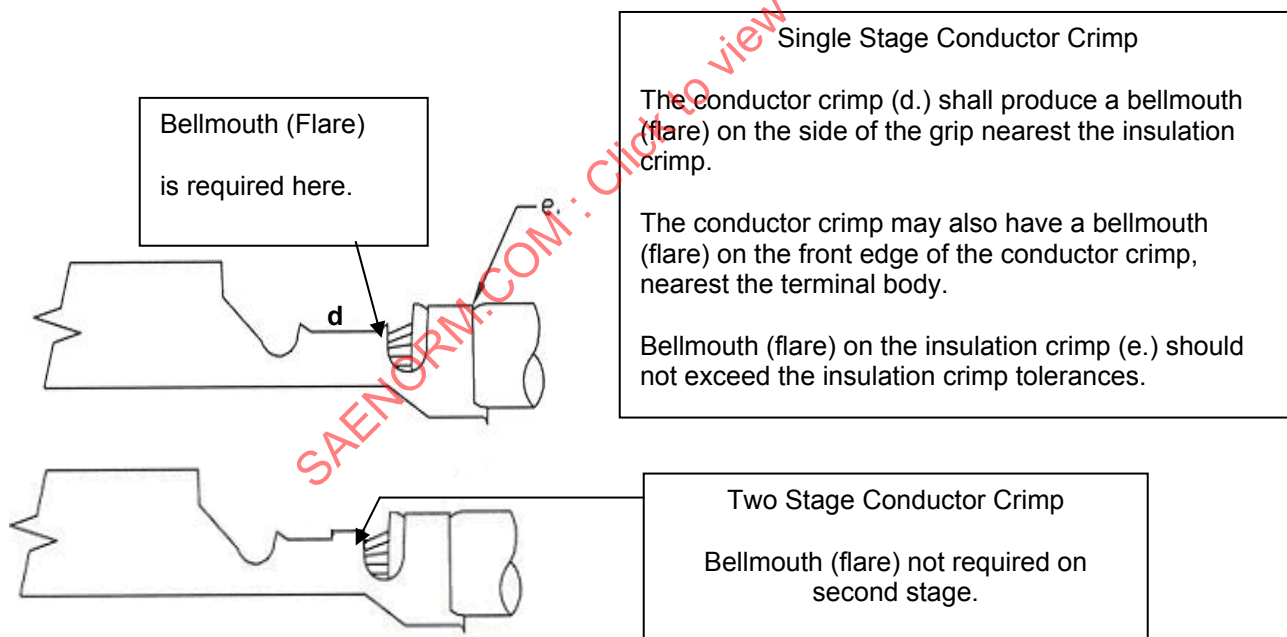
3. End of insulation

The end of the insulation must be visible in the window between the conductor grip wings and the insulation grip wings such that conductor is visible and should be centralized as much as possible. In no case may un-striped insulation be crimped in the conductor grip.

4. Cut-off

- The cut-off length shall not exceed 0.5 mm or $\frac{1}{2}$ terminal stock thickness, whichever is greater, unless otherwise specified on the component print.
- The burr on the cut-off must not exceed 0.3 mm on terminal stock thickness ≤ 0.8 mm unless otherwise specified on the component print. The burr must not exceed 0.6 mm on > 0.8 mm stock thickness unless otherwise specified on the component print.
- The cut-off and burr must not affect the insertion function of the terminal into the connector.

5. Bellmouth (Flare)



6. Conductor Grip

All individual strands must be enclosed in the grip. Crimped attachments with strands lying outside the grip or broken off before the grip, are not permitted.

7. Insulation Grip

- a. The purpose of an insulation grip is to add strain relief to the crimped conductor. This moves the stress riser between the crimped and un-crimped wire strands out into the un-crimped portion of the wire core.
- b. The crimped Insulation grip must contact the surface of the insulated cable in at least 3 locations around the circumference of the cable (three point contact). Total contact is also acceptable.
- c. The crimped Insulation grip dimensions are reference dimensions.
- d. The crimped Insulation grip must not interfere with any subsequent operations.
- e. The crimped Insulation grip must not interfere with seating of a terminal into a plastic connector cavity
- f. The crimped insulation grip must not damage the cable (see Paragraph 4.3.5-3)

8. Cable Conductor Appearance prior to crimping

- a. Strands shall not be cut, missing, excessively nicked (strand area reduction which may affect pull-out force), or elongated.
- b. Insulation shall not be stuck or imbedded in strands.

9. Individual Cable Seal Grip.

Note: This specification does not include any requirements for seal sliding force due to the large number of variables. It is necessary that individual cable seals be properly seated in plastic connectors to function.

- a. The seal must be firmly secured by the insulation grip.
- b. The seal must show no signs of damage.
- c. Seal designs with a neck and/or hub must have the end of the seal neck or hub visible in the area between the insulation and the conductor grips.
- d. The cable insulation must be visible under the seal.

4.3 Cross-Section Analysis

4.3.1 Purpose

Cross-sectional analysis is used as a diagnostic aid in determining why a grip passes or fails a portion of this test. Failure to pass an electrical test may be due to uneven strand dispersion, inadequate wing closure, voids, wings bottoming out, etc.

4.3.2 Sample Size

At least one specimen for each crimp height shall be evaluated. Data shall be obtained and recorded for minimum, maximum and nominal production crimp heights.

4.3.3 Equipment

Various specialized equipment exists for cross-sectioning samples. The choice of equipment is up to the supplier, but should be capable of sectioning the grip with minimal disturbance to the terminal and cable stranding.

4.3.4 Procedure

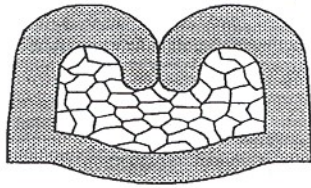
1. Cross-section and photograph each specimen for analysis
2. Cross-section analysis shall be performed on all conductor grip applications at each crimp height setting (nominal, min. and max. tolerance).
3. Cross-sections shall be performed between the serrations, as near to the mid-point of the core grip as possible.
4. Compare the specimens to paragraph 4.3.5, Acceptance Criteria

4.3.5 Acceptance Criteria

Acceptance criteria for the cross-sectioned samples are described as follows:

1. Cross-section views of crimped conductor grips

Crimped Conductor Grip attributes considered ideal



- Symmetric
- Compaction of all strands (no round strands)
- Wings touch only conductor
- Terminal stock free of cracks / breaks
- Core wings "Locked" (No Gap) at top of crimp

Crimped Conductor Grip attributes considered acceptable but not ideal.*

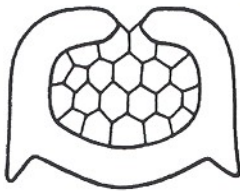


Overlapping
wings



Extreme "ram-horning"

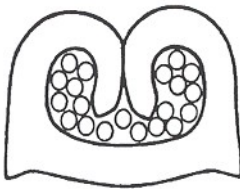
Crimped Conductor grip attributes considered unacceptable



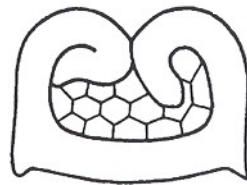
Open wings with
conductor exposed or
folded down into core
but not touching (not
locked)



One or both wings
(grips) penetrate
("crash") to the
terminal floor or wall



No strand
compaction*



One or both wing
(grip) details do not
capture strands



Terminal stock
cracked / broken

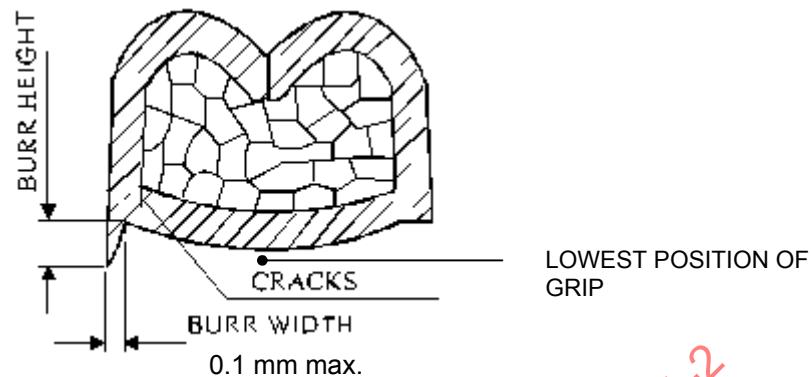


One or both
wings folded
back

Note: With OEM customer approval, the above attributes listed as unacceptable may be considered acceptable if it can be shown that all other requirements of this specification are met and past production experience has shown them to be functional in the intended application.

* Round strands in core grip are never acceptable.

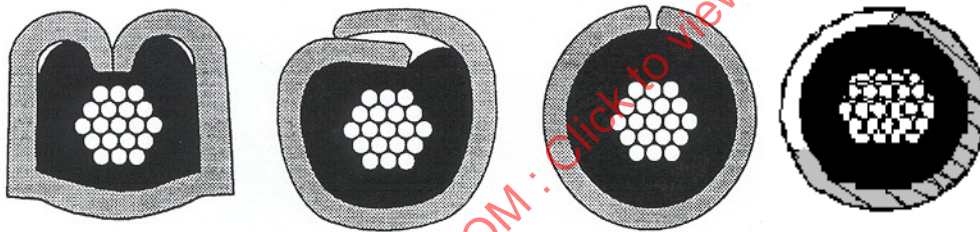
2. Burr on the base of grip



- a. The width of any burr on the base of the grip must not exceed 0.1 mm for $\leq .8$ thick terminal stock or $> .8$ stock thickness the width of the burr must not exceed $.15X$ stock thickness. (For accurate crimp height measurement, it is recommended that the burr height does not exceed the lowest position of the grip)
- b. The burr must not cause damage to any subsequent operation. Special care must be taken when using mat seals.

3. Cross-section views of insulation crimp

Standard insulation grip attributes considered ideal



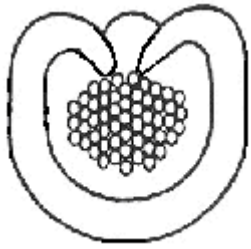
- Symmetric crimp
- No insulation penetration
- Wings (grips) embrace insulation to provide adequate strain relief

Some examples of non-standard insulation grips include "tee-pee", "tear drop", "square", or "tall B".

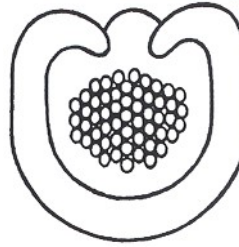
Refer to the terminal manufacturer's recommendations for acceptable/unacceptable non-standard insulation grip attributes.

Note: Some insulation grips serve as a functional part of the terminal/cavity retention system.

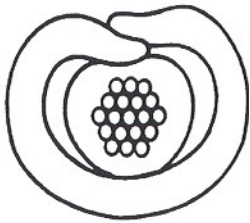
Crimped insulation grip attributes considered acceptable but not ideal.



Insulation wings contact conductor (no damage to conductor)

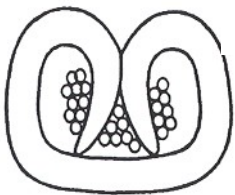


Insulation extruded outward between open insulation wings

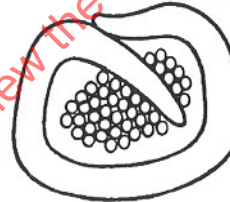


Less than 3-point contact

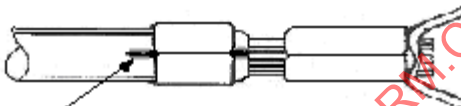
Crimped insulation grip attributes considered unacceptable



One or both wings penetrate ("crash") to the terminal floor or wall

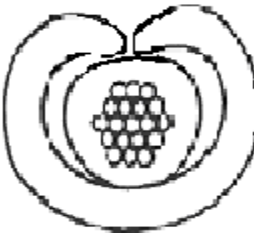


One or both wings penetrate and damage the conductor*



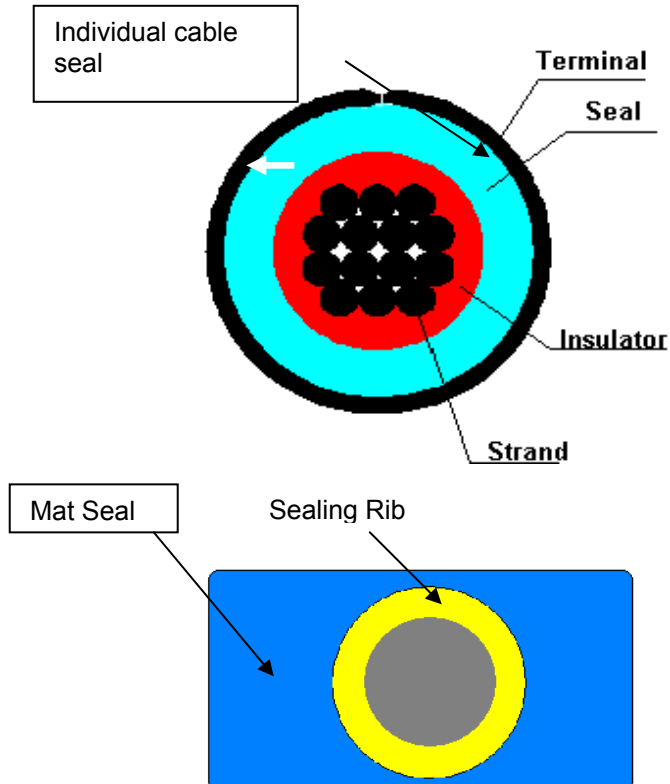
Insulation Split

*Damage is defined as severing strand(s)



No contact

4. Cable Seals



No nicks or cuts are permitted in the seal neck or in the sealing ribs. Insulation grip wings are not permitted to penetrate into the seal neck.

Crimped terminal and wire attributes must be designed to avoid damage (such as nicks and cuts) to the sealing ribs when inserting terminated leads through mat seals.

4.4 Conductor Grip Pull-Out Force

4.4.1 Purpose

This procedure details a standard method to measure the retention capability of crimped connections.

Note: Pull-out force test will not be used to determine overall performance of the crimped grip application. It is intended to be used for mechanical grip evaluation only. It will only be used to determine the mechanical limits of the application for handling purposes. Applications may require additional protection to assure the crimped circuit survives the harness handling and vehicle assembly process.

4.4.2 Equipment

1. Measuring device capable of measuring crimp heights and widths.
2. De-crimping tool or other suitable means of opening insulation Grip wings without damaging the cable conductor.
(**Note:** it is acceptable to make the samples with the insulation grip not crimped to avoid this step.)
3. Force tester
4. Cable strippers, long-nose pliers and/or side cutters.

4.4.3 Samples

1. A minimum of 20 samples is required to be tested for each production crimp height (3 crimp heights minimum). Additional conductor crimp heights may be included in the tests to help determine the nominal and +/- crimp heights. See 4.4.4, step 9: Additional samples may be required for grips with multiple wires of various sizes.

Note: Crimped samples may be used for electrical testing prior to tensile testing.

Note: Dimensional data shall be obtained, recorded and included in the test report. Measure the conductor crimp height on all specimens under test. Measure conductor crimp width and insulation crimp height and width on 5 specimens (minimum) from each conductor crimp height sample group.

4.4.4 Procedure

1. Pull-out force test shall be performed on leads with the insulation grip wings open (not crimped).
2. Pull-out force test shall be performed on taut leads (i.e., remove slack in cable before performing pull-out test to prevent incorrect test results due to "jerking").
3. Measure and record the conductor and insulation crimp heights and widths in millimeters for each sample. Refer to Appendix E, 6-8.
4. If the insulation grip is not already open, open it with a de-crimper or other suitable tool so that the pull-out force will reflect only the crimped conductor grip connection.
5. Visually inspect the de-crimped area to ensure that none of the conductor strands have been damaged. Do not use any samples that have damaged conductor strands.
6. Measure and record pull-out forces in Newtons for each sample.
7. Apply an axial force at a rate between 50 and 250 mm/minute (100 mm/min. is recommended).
8. For double, triple, or multiple wire grip setups with conductor sizes within one step, pull the smallest conductor. (e.g. for a .35/.50 double, pull the .35 mm² wire)
9. For double, triple, or multiple wire grip setups with conductor sizes more than one step apart, one of the smallest and one of the largest gage size cables must be tested. (e.g. for a .50/1.0 double, pull both wires individually, for a .50/1.0/2.0 triple, pull the .50 mm² and the 2.0 mm² wires, for a .50/.50/2.0 triple, pull one of the .50 mm² and the 2.0 mm² wires.) In this case, 20 samples per wire size tested will be required.
10. Calculate the mean and standard deviation using the following formulas:

$$\text{Mean } (\bar{X}) = \frac{\sum_{i=1}^n X_i}{n}$$

Where X_i = individual pull-out force.
n = number of samples.

$$\text{Standard Deviation (s)} = \sqrt{\frac{\sum_{i=1}^n X_i^2 - n \bar{X}^2}{n-1}}$$

Report minimum, maximum, mean ($\bar{X}$), standard deviation (s), and the mean minus three standard deviations ($\bar{X} - 3s$) for each crimp height set.

11. Report any observations from visual examination.

4.4.5 Acceptance Criteria

- The ($\bar{X} - 3s$) value of the pull-out forces are specified in Table 4.4.5. The pull-out forces for unlisted conductor sizes can be defined by linear interpolation, (i.e. read out from plotted values in Table 4.4.5). Note: The tensile value requirement on wire sizes $\geq 10 \text{ mm}^2$ is minimum value only and does not require pull to failure.

Approx. Metric (mm ²)	AWG ^(a)	($\bar{X} - 3s$) And Minimum Pull-out Force (N)
≤ 0.22	≤ 24	40 ^(b)
0.35	22	50 (Annealed Core)
0.35	22	70 (Hard Drawn Core)
0.5	20	75
0.8	18	90
1.0	16	120
1.5		150
2.0	14	180
2.5		210
3.0	12	240
4.0		265
5.0	10	290
6.0		320
8.0	8	350
10.0		450
>10		600 ^(b)

Table 4.4.5 – Pull-out Force Requirements

^(a) $\leq$ is intended to indicate smaller wire size (Larger number designation)

^(b) Or as defined by responsible person.

4.5 Electrical Performance Tests

4.5.1 Current Cycling of Electrical Terminations (ECC)

4.5.1.1 Purpose

Current cycling is an accelerated aging test that emphasizes the effect of expansion and contraction of terminal interfaces and conductor grips as a result of thermal cycling. This test is optional (See table 5.1). The Accelerated Environmental Test (paragraph 4.5.2) may be done in place of this test for Power applications. (See table 5.1)

4.5.1.2 Samples

1. Any engineering development, prototype, or production terminal – particularly those intended for high current or “Power” applications – may be submitted for test.
2. Test data will be collected on 10 samples of each crimp height. Data shall be obtained and recorded for minimum, maximum and nominal production crimp heights.
3. In cases where mating terminals are available, apply these to the opposite ends of the test sample cables. These should be a minimum cut length of 150 mm. The terminal grips on the mating terminals may be soldered. Samples are then connected to form a continuous series circuit.
4. Test sample terminals that have no mating terminals should be applied to one end only of the test cable (a minimum cut length of 150 mm). The opposite stripped ends of the samples are then soldered to box or blade of the next sample to form a continuous series circuit.
5. Doubles should be terminated with the test terminal on one end only. A mating terminal may be applied (with the grip soldered) to the other end of the largest size cable. When identical size cables are doubled, cables should be randomly tested.

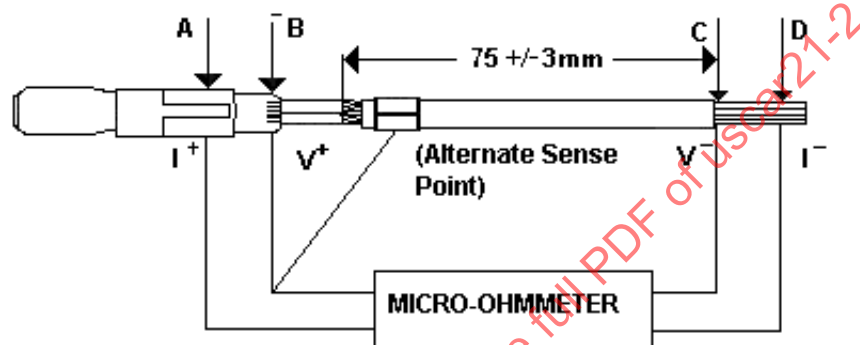
4.5.1.3 Equipment

1. Power supply – AC or DC current regulated capable of supplying the test current.
2. Cycle timer.
3. Ammeter or current shunt/voltmeter
4. Voltmeter.
5. Voltage sense lead – solid conductor .32 mm or smaller in diameter.

6. Welder – Tweezer Weld TW-3 or similar device.
7. Terminal test board.
8. Sample with solder added to the conductor grip (soldered sample/deduct sample).

4.5.1.4 Procedure

1. Perform a visual inspection of components per paragraph 4.2.
2. Voltage sense leads are attached to the sample terminals per figure 4.5.1.4. The same location must be used for all samples.



(Note: The V + test lead may be connected to back of insulation wing if wing does not touch the core)

Figure 4.5.1.4 – Test Lead Attachment

3. Sense leads are also attached to the test cable at a point 75 ± 3 mm from the rear edge of the conductor grip.
4. Samples are then connected in a series circuit.
5. The samples are then loosely attached to a test board with a minimum of 35 mm between single terminals.
6. The series test circuit is connected to the ammeter / current shunt and a timer-controlled power supply. Include the soldered test sample (4.5.1.3-8) in the circuit. The test duration shall be a minimum of 200 ± 8 hours with the test current cycling on for $45 \text{ minutes} \pm 2 \text{ minutes}$ and off for $15 \text{ minutes} \pm 2 \text{ minutes}$.
7. The typical test currents are listed in table 4.5.1.4 unless otherwise specified.

Cable Size*	AWG	Amperes with Cable rated to +55°C
0.05 mm ²	30	1
0.08 mm ²	28	2
0.13 mm ²	26	4
0.22 mm ²	24	6
0.35 mm ²	22	10
0.5 mm ²	20	14
0.8 mm ²	18	18
1.0 mm ²	16	22
2.0 mm ²	14	30
3.0 mm ²	12	40
5.0 mm ²	10	65
8.0 mm ²	8	100

*The test currents for conductors sizes not listed above can be defined by linear interpolation (i.e. read out from plotted values).

Table 4.5.1.4 Test Current for Current Cycling

8. If test currents are not known, then, at room temperature:
Attach thermocouples to samples at a point on the under-side and just in front of the crimped conductor grip. Welding or epoxy is permissible.
 - a. Apply 75% of the estimated current to the circuit.
 - b. Allow the circuit to come to steady state temperature. The temperature is stable when the grip on the sample under test changes less than 2° C in 5 minutes.
 - c. Measure the temperature, and calculate the temperature rise.
If the temperature rise is less than the maximum temperature rise recommended by the terminal supplier or 55°C, whichever is lower, then increase the current in 0.50 Amp steps until that temperature is reached.
9. The current at which the maximum temperature rise recommended by the terminal manufacturer or 55°C, whichever is lower, is reached is the test current.
10. An acceptable alternative to a, b, and c above is to perform the "Maximum Test Current Capability" test identified in USCAR-2.
11. Measure voltage drop after 2 hours ± 1 hour and at the completion of the test (200 hours ± 8 hours). The samples should be energized for a minimum of 30 minutes to allow for temperature stabilization. Measurements are taken between points B & C. (see Figure 4.5.1.4)
12. Measure the voltage drop across the soldered sample.
13. Conductor grip/wire voltage drop is equal to the voltage drop recorded in step 11 less the soldered sample value measured in step 12.

14. Record:

- a. All voltage drop measurements, and all calculated resistance values.
- b. Average, low, and high resistance values for each data set.
- c. Description of samples.
- d. Conditions of test.
- e. Instruments used, the date of last calibration, and when the next calibration is due.
- f. Soldered sample resistance value if applicable.
- g. Temperature rise on at least one part in the nominal CCH group
- h. Observations.

4.5.1.5 Acceptance Criteria

1. All samples within 3 consecutive crimp heights representing the lower, nominal, and upper specification limits per the conductor crimp height tolerances of Appendix E, Table E-1 must satisfy one of the following two acceptance criteria upon completion of the electrical current cycling test (ECC)
 - a. Maximum allowable resistance = Per table 4.5.6.5 or $0.011 \times (\rho_1 + \rho_2) / (2d)$ milliohms, whichever is greater. (Allows 11 times the initial calculated crimp resistance)
 - b. Allowable resistance Change = Per table 4.5.6.5 or $0.0099 \times (\rho_1 + \rho_2) / (2d)$ milliohms, whichever is greater. (Allows 9.9 times the initial calculated crimp resistance)

Where ρ_1 = The resistivity of the conductor in micro-ohm-mm²/mm

(For copper conductor, ρ_1 = 17.2 micro-ohm-mm²/mm per the International Annealed Copper Standard)

ρ_2 = The resistivity of the base terminal material in micro-ohm-mm²/mm

d = The diameter of a circle with the same area as the total cross sectional area of the conductor in mm.

$(\rho_1 + \rho_2) / 2d$ = Theoretical Crimp Resistance based upon geometry and resistivity of terminal and cable.

- c. Refer to Appendix D, Table D-1 and D-2 for the calculated values for typical referenced alloys.

4.5.2 Accelerated Environmental Exposure Test

4.5.2.1 Purpose

This procedure describes the testing of electrical components when subjected to sequential environmental exposure.

4.5.2.2 Samples

A minimum of 10 terminal samples of each crimp height shall be tested. Data shall be obtained and recorded for minimum, maximum and nominal production crimp heights. Minimum cable length for samples is 75 mm.

4.5.2.3 Equipment

1. Humidity chamber.
2. Forced air.
3. Temperature chamber.
4. An automatic temperature/humidity cycling chamber may be used as an alternative to items 2, 3, and 4 above.

4.5.2.4 Procedure

Complete the test procedure per figure 4.5.2.4 (Flow diagram)

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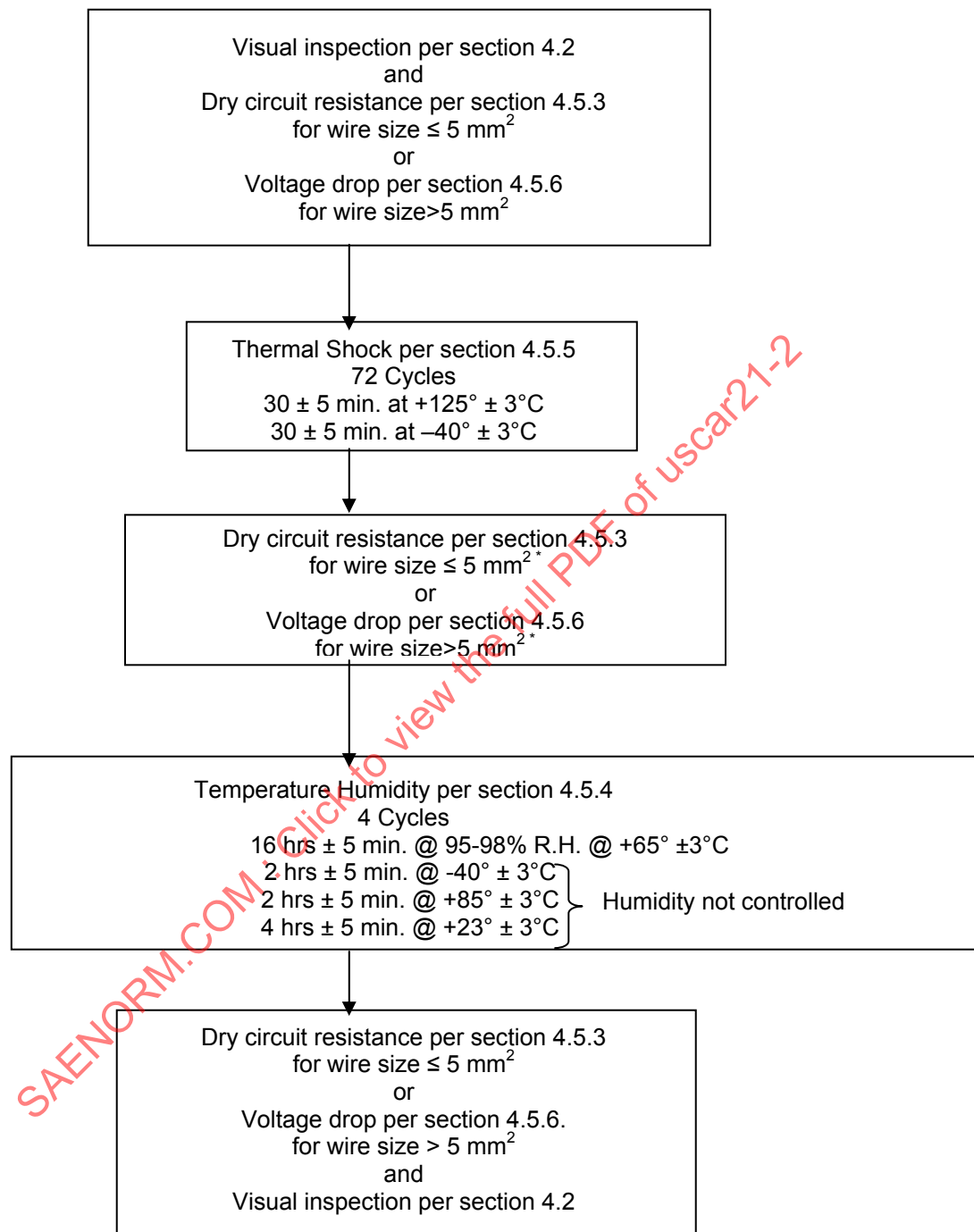


Figure 4.5.2.4: Accelerated environmental test sequence [flow diagram]

*optional

4.5.3 Dry Circuit Termination Resistance of Static Contacts

4.5.3.1 Purpose

1. This procedure covers measuring the termination resistance of static contacts under dry circuit conditions, which will not alter that resistance by breakdown of insulating films or softening of contact asperities.
2. Dry circuit conditions require that the maximum voltage impressed across the test sample be limited to 20 millivolts, and the maximum current through the sample be limited to 100 milliamperes. Performance at these levels is indicative of interface performance at any lower level of excitation.

Note: For dry circuit evaluation on grips containing multiple wires, perform the resistance measurement on the smallest wire in the grip.

4.5.3.2 Samples:

1. A minimum of 10 samples of each crimp height shall be submitted for test. Data shall be obtained and recorded for minimum, maximum and nominal production crimp heights. Prepare at least 1 additional sample of each crimp height to be used as the deduct sample in 4.5.3.4 – 4.
2. A sample length of 150 mm is recommended. However, any sample length ≥ 75 mm is acceptable as long as there is no effect on the crimped grip during processing and handling of samples. The same length shall be used for all samples under test as well as for the deduct sample.
3. Prepare resistance measurement points on the test samples at a point on the cable 75 ± 3 mm from the rear edge of the terminal conductor grip.
4. Apply solder to measuring point C, figure 4.5.3.4 (stripped end of wire) to obtain consistent readings.

4.5.3.3 Equipment

Micro-ohmmeter

4.5.3.4 Procedure

1. Perform a visual inspection of components per paragraph 4.2.
2. Measurements shall be made on thoroughly dry samples without cleaning or rinsing of corrosion products.
3. Relative movement of samples should be minimized to reduce effects of movement on measured values.

4. Measure and record the resistance of a sample with a soldered grip. The measurement is made at a point 75 ± 3 mm from the rear edge of the terminal conductor grip.
5. Measure and record the resistance between the cable measuring point C and point B on the terminal, just in front of the conductor grip (see Figure 4.5.3.4).
6. Calculate and record the crimped grip resistance. The crimped grip resistance is equal to the overall resistance measured in step 5, less the soldered sample resistance measured in step 4.

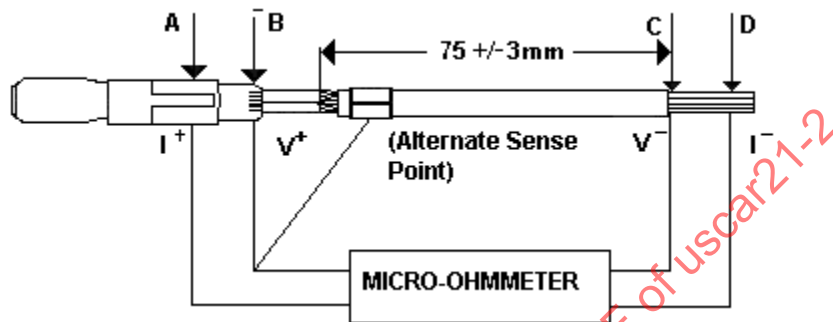


Figure 4.5.3.4: Dry Circuit Measurement Points

(Note: The V + test lead may be connected to back of insulation wing if wing does not touch the core)

4.5.3.5 Acceptance Criteria

1. All samples within 3 consecutive crimp heights representing the lower, nominal, and upper specification limits must satisfy one of the following two acceptance criteria upon completion of the Accelerated aging test (ENV).

Note: See Appendix E, Table E-1 and note for crimp height tolerance.

- a. Maximum allowable resistance = 0.55 milliOhms, or $0.011 \times (\rho_1 + \rho_2) / (2d)$ milliOhms, whichever is greater. (Allows 11 times the initial calculated crimp resistance)
- b. Allowable resistance change = 0.33 milliOhms, or $0.0099 \times (\rho_1 + \rho_2) / (2d)$ milliOhms, whichever is greater. (Allows 9.9 times the initial calculated crimp resistance)

Where ρ_1 = The resistivity of the conductor in micro-ohm-mm²/mm
 (For copper conductor, ρ_1 = 17.2 micro-ohm-mm²/mm per the International Annealed Copper Standard)
 ρ_2 = The resistivity of the base terminal material in micro-ohm-mm²/mm
 d = The diameter of a circle with the same area as the total cross sectional area of the conductor in mm.
 $(\rho_1 + \rho_2) / 2d$ = Theoretical Crimp Resistance based upon geometry and resistivity of terminal and cable.

Refer to Appendix D, Table D-1 and D-2 for the calculated values for typical referenced alloys.

Note: Smaller wire sizes or alternate wire core materials may require using the formulas in paragraph 4.5.3.5 a. & b. to establish acceptance criteria.

Note: Terminals crimped on wire sizes $>5 \text{ mm}^2$, use 4.5.6.5 for Voltage Drop Acceptance Criteria

4.5.4 Accelerated Temperature / Humidity Cycle Conditioning – 24 hour cycle

4.5.4.1 Purpose

1. This procedure defines an accelerated version of temperature/humidity cycle conditioning.
2. Accelerated temperature/humidity cycling conditioning may be used to determine the effect of sequential exposure to high humidity and high and low temperature environments on electrical and electronic components.
3. High and low temperature and high humidity environments may promote corrosion of metals, degrade properties of other materials, and establish electrical bridging between circuits.

4.5.4.2 Samples

Prepare samples per paragraph 4.5.3.2.

Note: The same sets of samples shall be consecutively exposed to the T/S and T/H conditioning and be measured by either the dry circuit or voltage drop procedures described in this specification.

4.5.4.3 Equipment (Recommendations only)

1. Humidity chamber.
2. Forced air oven.
3. Temperature chamber.
4. Automatic temperature/humidity cycling chamber. This equipment may be used as an alternative to that listed in paragraphs 1, 2, and 3 above.

4.5.4.4 Procedure

1. Expose test samples to temperature/humidity cycling as follows:

- a. 16 hours @ 95-98 percent relative humidity at $+65 \pm 3$ °C. This is the only step where humidity is controlled.
- b. 2 hours @ -40 ± 3 °C.
- c. 2 hours @ $+85 \pm 3$ °C.
- d. 4 hours @ $+23 \pm 3$ °C.
- e. This constitutes one complete temperature/humidity cycle.
- f. Maximum transfer time of samples from one environment to the next during the defined temperature/ humidity cycle is 1 hour.
- g. All time periods listed in the defined cycle have a tolerance of ± 5 minutes
- h. Four cycles of the environmental exposure described above constitutes a complete temperature/humidity cycling test.

} Humidity not controlled

4.5.4.5 Acceptance Criteria

This is a conditioning procedure only. There are no acceptance criteria.

Note: Use Dry Circuit Acceptance Criteria 4.5.3.5 or Voltage Drop Acceptance Criteria 4.5.6.5 following 4.5.2.4 test sequence.

4.5.5 Test procedure - Thermal Shock Conditioning

4.5.5.1 Purpose

This test specification details the procedure for testing the functional reliability of electrical and electronic components when subjected to alternating high and low temperature environments. Rapid transfer between the two environments tests the component's ability to withstand drastic temperature changes.

4.5.5.2 Samples

- 1. Make certain that the cable insulation can withstand the rigors of the test conditions.
- 2. Prepare samples per paragraph. 4.5.3.2.

Note: The same set of samples shall be consecutively exposed to the T/S and T/H exposure and be measured by either the dry circuit or voltage drop procedures described in this specification.

4.5.5.3 Equipment

Thermal shock chamber or separate hot and cold chambers.

4.5.5.4 Procedure

1. Perform visual examination per paragraph 4.2.
2. Perform dry circuit resistance, per paragraph 4.5.3.
3. Set controls to the necessary temperatures, dwell times, and number of cycles.
4. Allow the chambers sufficient time to achieve the programmed temperature.
5. Place the samples in the transfer basket. Insure that the test samples cannot jam the transport mechanism.
6. Start the test program per figure 4.5.5.4.

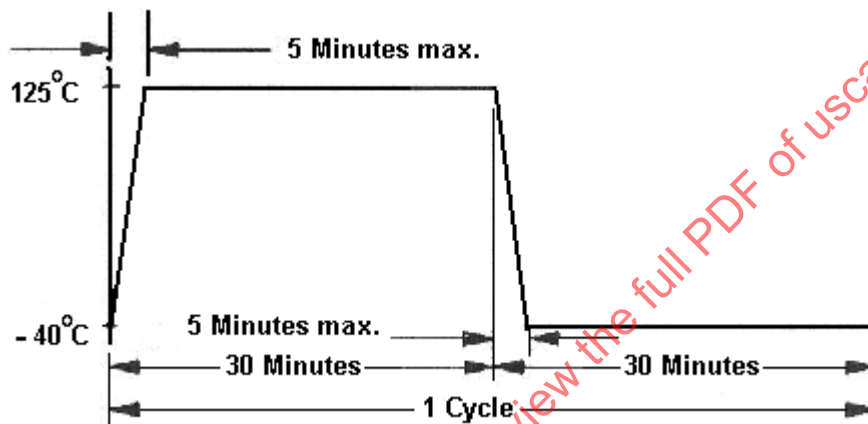


Figure 4.5.5.4: Thermal Shock Programming and Operation

7. When test program is complete, shut off the thermal shock chamber and remove samples.
8. Perform visual examination per paragraph 4.2.
9. Include in the report:
 - Operating temperatures, dwell times, and number of cycles tested
 - Report on evaluation tests, if performed.

4.5.5.5 Acceptance Criteria

This is a conditioning procedure only. There are no acceptance criteria.

Note: Use Dry circuit 4.5.3.5 or Voltage drop 4.5.6.5 Acceptance Criteria following 4.5.2.4 test sequence.

4.5.6 Voltage Drop Test for Crimped Grip Connections

Note: This test is intended to be used for terminals crimped on $>5 \text{ mm}^2$ wire size.

Note: 4.5.1 may be used to validate crimped terminal/wire, power combinations in lieu of 4.5.6.

4.5.6.1 Purpose

1. This procedure defines measuring the termination voltage drop, of static crimped contacts, under high energy conditions. It is to be used to validate terminal/wire combinations where the wire core cross section is $>5 \text{ mm}^2$.
2. The current through the specimen will be applied at a level per table 4.5.6.5. This current is applied to the sample under test so voltage drop of the termination can be measured. Power supply voltage will be allowed to float during this test.

Note: For multiple wire grip, high current evaluation, perform the mVD measurement on the smallest wire. Test current level will be based on the wire selected for the mVD measurement.

4.5.6.2 Samples:

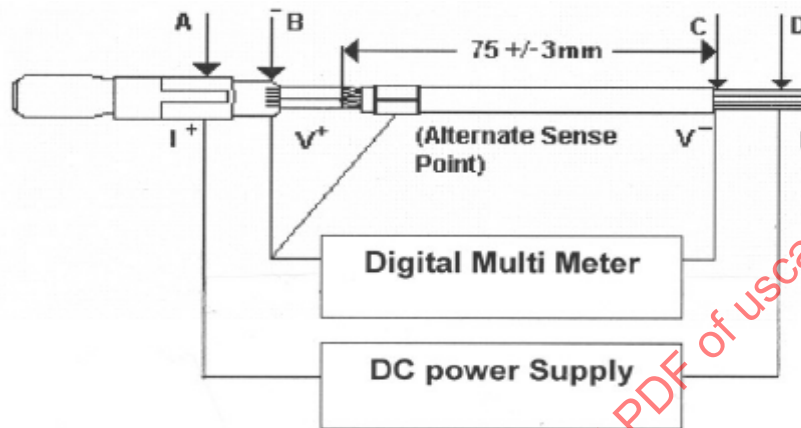
1. A minimum of 10 samples of each crimp height under test shall be submitted for test. Data shall be obtained and recorded for no less than 3 consecutive (minimum, maximum and nominal) production crimp heights. Additional crimp heights may be included in the test to assure there will be at least 3 consecutive crimp heights that meet the voltage drop requirements. These samples may also be used for the tensile test samples after the accelerated environmental exposure and voltage drop measurements are made. Prepare 3 additional samples (proposed nominal crimp height recommended) to be used to determine the deduct voltage drop as required in 4.5.6.4 - 7. The grips on these "Deduct" samples will be soldered and the voltage drop will be measured in the same manner as the samples under test. These "Deduct" samples will be identical in length, wire type and terminal type to the other samples under test except the terminal grip will be soldered. Use the average voltage drop measured on these 3 "Deduct" samples as the deduct value for this test.

Note: See Appendix E, Table E-1 for crimp height tolerance.

2. A minimum sample length of 150 mm is recommended however, any sample length $>150 \text{ mm}$ is acceptable as long as there is no effect on the crimped grip during processing and handling of samples. Longer wire length may be necessary if the samples are powered in series for this test. It is important to use the same length for the deduct sample as for those samples under test.

3. Prepare the voltage drop measurement points on the test samples at a point on the cable 75 ± 3 mm from the rear edge of the terminal conductor grip.
4. Apply solder to measuring point C, figure 4.5.6.2 (center strip or stripped end of wire) to obtain consistent readings.

Note: The same set of samples shall be consecutively exposed to the T/S and T/H exposure and be measured using the voltage drop procedures described in this specification.



Note: The V + test lead may be connected to back of insulation wing if the wing does not touch the wire conductor core.

Figure 4.5.6.2 Voltage drop power hook up and measurement points

4.5.6.3 Equipment

1. DC Power supply (0~20V. (200A min recommended)) or 0~20 V current as required.
2. Digital Volt meter

4.5.6.4 Procedure

1. Perform a visual inspection of components per paragraph 4.2.
2. Relative movement of samples should be minimized to reduce effects of movement on measured values. This is an open air bench test. In an effort to maintain repeatability, care should be taken to avoid drafts from HVAC, open windows, etc
3. Apply current (based on wire size) per table 4.5.6.5 at points A and D
4. Allow the temperature of sample(s) to stabilize (with current applied) as follows:

Use a thermocouple or non contact thermometer to measure the temperature of the terminal grip under test. The temperature is stable when the grip on the sample under test changes less than 2°C in 5 minutes.

Note: Applying the current load in series to all samples under test is recommended and requires only one stabilization interval.

5. Measure and record the voltage drop of the 3 samples with soldered grips. The measurement is made at a point 75 ± 3 mm from the rear edge of the terminal conductor grip. The average voltage drop value of these 3 samples will be used in step 7.

Note: If the samples are connected and powered in series, include the soldered samples with the samples under test.

6. Measure and record the voltage drop on each sample between the cable measuring point C and point B on the terminal, just in front of the conductor grip. (see Figure 4.5.6.2).
7. Calculate and record the crimped grip voltage drop: The crimped grip voltage drop is equal to the overall sample voltage drop measured in step 6, minus the average voltage drop of the 3 soldered grip samples measured in step 5.

Note: Samples may be connected in series and powered up all together as long as the “B” and “C” measurement points are accessible and do not interfere with measurement points on any other samples wired in this series. Split bolts or terminals crimped to both ends of the sample under test are acceptable methods to for applying current in series to 2 or more terminals for the purpose of using voltage drop to validate the crimping process on $> 5 \text{ mm}^2$ cable. Applying the test current in series to all samples at once will reduce set-up, measurement and environmental errors or differences.

4.5.6.5 Acceptance Criteria

Maximum allowable Voltage Drop for terminal/wire combinations using $> 5 \text{ mm}^2$ wire shall be equal to or less than the values shown in table 4.5.6.5 - or –

- a. Maximum allowable resistance = $0.011 \times (\rho_1 + \rho_2) / (2d)$ milliohms, whichever is greater. (Allows 11 times the initial calculated crimp resistance)
- b. Allowable resistance change = $0.0099 \times (\rho_1 + \rho_2) / (2d)$ milliohms, whichever is greater. (Allows 9.9 times the initial calculated crimp resistance)

Where ρ_1 = The resistivity of the conductor in micro-ohm-mm²/mm
(For copper conductor, $\rho_1 = 17.2$ micro-ohm-mm²/mm per the International Annealed Copper Standard)

ρ_2 = The resistivity of the base terminal material in micro-ohm-mm²/mm

d = The diameter of a circle with the same area as the total cross sectional area of the conductor in mm.

$(\rho_1 + \rho_2) / 2d$ = Theoretical Crimp Resistance based upon geometry and resistivity of terminal and cable.

mm ² Wire size	Test current	Maximum mV/A (mΩ)	Maximum mV/A (mΩ) Change
≤5	Use dry circuit resistance of static contact method 4.5.3		
>5 <13	50A	0.15	0.09
≥13 <19	75A	0.11	0.07
≥19 <32	100A	0.08	0.05
≥32 <40	100A	0.06	0.04
≥40 <50	100A	0.05	0.03
≥50 <62	100A	0.04	0.02
≥62 ≤103	150A	0.03	0.02

Table 4.5.6.5

Note: 1mV/A = 1mΩ

5. VALIDATION REQUIREMENTS FOR CRIMPED TERMINALS - SUMMARY

5.1 Validation Test Requirements

5.1.1 The validation requirements listed in Table 5.1 shall be conducted to demonstrate the design intent is met.

5.2 Special Applications and Exclusions

5.2.1 Special applications and variances from this specification require customer approval. Pull-out force testing and cross-sections [PTX] are required for all validations.

5.2.2 This specification is intended to validate only the crimping process. It is the terminal supplier's responsibility to establish and validate capability for their product to function in a specific environment such as in elevated temperature. Base metal and plating must be considered when selecting a component for use in extreme applications.

5.3 Other Crimp Validation Methods

5.3.1 Reference [REF] - The application is the "same as" another similar application already validated to meet the circuit and/or customer requirements

5.3.2 "Same as" is defined as having the same:

- terminal stock thickness
- material (alloy and temper)
- the same terminal plating
- the same terminal conductor wing dimensions and features [serrations, etc.]
- the same conductor core cross sectional area¹
- the same insulation outside diameter

¹ The "same as" wire conductor is limited to 7 and 19 strand construction. Other stranding options must be tested on an individual basis.

Note: SAE, ISO, and JIS wire types with the same size designation will have different conductor core cross sectional area and must be validated as separate wire sizes.

5.3.3 Cables with the same conductor core construction, but differences in the insulation may be considered the "same" for crimped conductor grip validation purposes. The crimped Insulation grip must be reviewed against the cross section requirements for final validation.

5.3.4 Previous Electrical Validation (PEV): Previously validated high current terminations that meet the Acceptance Criteria 4.5.6.5 may be considered compliant even if a different test method was used to establish those values. All new applications must be validated to the latest revision level of this specification.

Test	Requirement Section or Paragraph Number.	Design Validation (Yes/No)	Minimum Conformance to Tolerance
Cable/Terminal/Crimp Tooling Identification traceable to Performance Testing	Appendix E	Y	100%
Compaction (Verified in production by Terminal, Cable, and crimp tool dimensions usually controlled by specific part numbers and traceable to validation testing.)	Appendix E, 1-2	Y	100%
Appearance - end of conductor - end of insulation - cut off - bellmouth - conductor grip - insulation grip - individual cable seal - terminal bend and twist due to crimping	4.2.5 4.2.5-2 4.2.5-3 4.2.5-4 4.2.5-5 4.2.5-6 4.2.5-7 4.2.5-9 Appendix E	Y Y Y Y Y Y Y Y N	100% 100% 100% 100% 100% 100% 100% 100% 100%
Crimp geometry - Conductor and insulation crimp height and width (CCH, CCW, ICH, ICW) - cross-section requirements	Appendix E Appendix E, 6-8 4.3	Y Y	100 % 100%
Mechanical performance - Pull out force* (Final OEM's quality assurance approval form process validation may be required.)	4.4	Y	Mean-3s>Limit
Electrical performance For Power Applications: Use ECC or ENV - Electrical testing Current Cycling – (ECC) or - Accelerated environmental testing (ENV)	4.5 4.5.1 4.5.2	 Y Y	 100% 100%
For Low Energy Applications: - Accelerated Environmental testing (ENV)	4.5.2	Y	100%
For Low Impedance Applications: Validation must be done on bare copper wire to optimize grip parameters even if production is on tinned wire. - Accelerated Environmental testing (ENV)	4.5.2	Y	100%

* 4.4 may be performed after 4.5.1. or 4.5.2. when the same samples are used for both electrical and mechanical testing.

Table 5.1 Tests to be used for validation

APPENDIX A: GRIP DESIGN RECOMMENDATIONS

- A. Recommended Terminal Wing/Cable Loading for new terminal designs or revisions to meet the performance requirements of this specification is shown in Table A.

Terminal Wing/Cable Loading Ranges		
Cable Range	SAE	DIN
0.05 – 0.08	X	X
0.13 - 0.22	X	X
0.35 - 0.50	X	X
0.75 - 1.25	X	X
1.5 - 2.5		X
2.0 - 3.0	X	
4.0 - 6.0	X	X

Table A-1: Recommended Wing/Cable Loading

B. Grip Engineering Guidelines

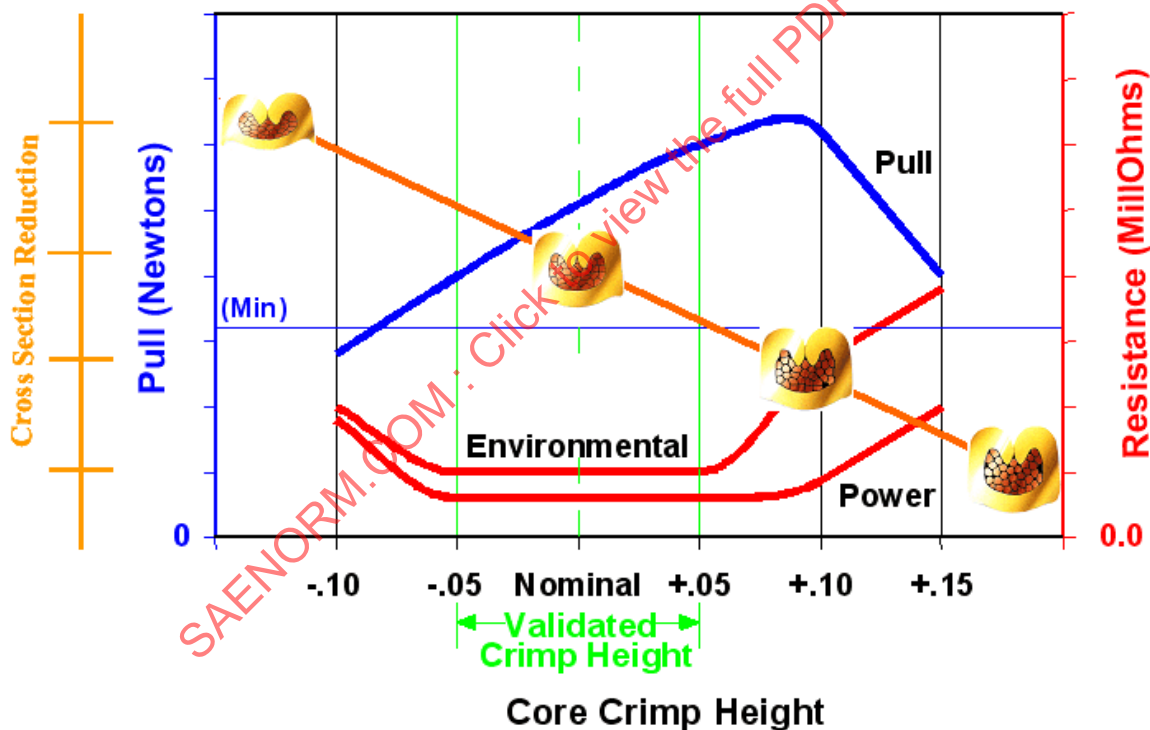
The following guidelines are intended only to assist in passing the requirements of this specification and are based upon previous experience from terminal suppliers:

1. The terminal supplier determines double application terminals.
2. Core wings that have features to break oxides and minimize cable strand movement will give better electrical results. Sharp cornered serrations are preferred.
3. Tin or silver plating is the optimum design for 10 year/150K life. Use caution when specifying nickel, stainless steel or gold in core wings since use of these materials may result in high crimped grip resistance. The design should provide for adequate free tin at end of life. Nickel plated high temperature wire also may not pass this electrical testing and may require specific changes in acceptance criteria based upon circuit application sensitivity (i.e. O₂ sensor circuits)
4. Optimum 10 year/150K life is obtained with similar alloys, tempers used for spring members and contact arms. This maintains grip wing normal force with time and temperature. It also provides strength to resist grip wing relaxation due to movement and stresses applied during vehicle life.
5. Wing blank width should be designed to provide for uniform strand dispersion for the gauge size recommended. This is necessary for optimum electrical strand contact, pulls, and nuisance free use of crimp force process monitors.
6. Crimped grip electrical performance should be done separately from connector testing. This is done so that a low and stable milli-ohm acceptance criteria can detect the loss of strand contacts in the grip. Grips that meet this criteria must then be able to pass USCAR tests in connectors.

7. Pull testing must only be used to determine mechanical strength. Usually the best electrical performance is on the tight side of the pull vs. crimp height curve (ref. Figure A-1). Both over and under compaction can result in poor electrical and or mechanical performance.
8. The preferred insulation grip geometry is the traditional "F" or "B" crimp. Overlapping, diagonal cut bypassing wings, or butting wings may be used, but may be sensitive to crimp processing conditions. It is usually best to tool specific grip wings for heavy-wall, regular-wall, thin-wall and/or Extra Thin Wall insulations.
9. Where possible, grip wings should be designed for European, US, and/or Asian cable constructions.

Note: Not all cable with the same size callout has the same cross sectional area. SAE, ISO, JIS, DIN, etc wire types may have the same size designation but each will have its own core cross sectional area. A crimped grip developed and validated to a terminal/wire combination with one wire specification cannot be used to approve the same terminal with a different wire specification. Example: Validated Crimp dimensions for a XXX terminal crimped on a .5 SAE wire cannot be used to validate a crimped grip on the same XXX terminal with a .5 JIS or .5 ISO wire. Moving from a wire constructed to one wire specification to a wire constructed to a different specification will require crimp re-validation even when they both have the same size designation. Example: SAE .5 (.508 mm² min) wire does not have the same cross sectional area as ISO .5 wire (.4647 mm² min (calculated from max. resistance requirement)).

10. A typical mechanical/electrical vs. crimp height curve is shown in Figure A-1



This graph is shown as an example only.

Figure A1

C. Crimp Validation Analysis and Decision Tree

